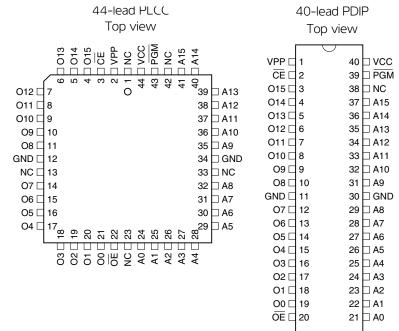


2. Pin configurations

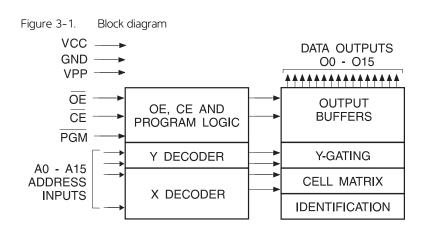
Pin name	Function
A0 - A15	Addresses
00 - 015	Outputs
CE	Chip enable
ŌĒ	Output enable
PGM	Program strobe
NC	No connect





3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a $0.1\mu\text{F}$, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a $4.7\mu\text{F}$ bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.



4. Absolute maximum ratings*

Temperature under bias55°C to + 125°C	
Storage temperature65°C to + 150°C	
Voltage on any pin with respect to ground2.0V to + 7.0V ⁽¹⁾	
Voltage on A9 with respect to ground2.0V to + 14.0V ⁽¹⁾	
V _{PP} supply voltage with respect to ground2.0V to + 14.0V ⁽¹⁾	

*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating

conditions for extended periods may affect device reliability.

Note:

1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is $V_{CC} + 0.75V$ DC, which may overshoot to +7.0V for pulses of less than 20ns.

5. DC and AC characteristics

Table 5-1. Operating modes

Mode/Pin	CE	ŌĒ	PGM	Ai	V _{PP}	Outputs
Read	V _{IL}	V _{IL}	X ⁽¹⁾	Ai	X	D _{OUT}
Output disable	Х	V _{IH}	Х	X	Х	High Z
Standby	V _{IH}	Х	X	X	X ⁽⁵⁾	High Z
Rapid program ⁽²⁾	V _{IL}	V _{IH}	V _{IL}	Ai	V _{PP}	D _{IN}
PGM verify	V _{IL}	V _{IL}	V _{IH}	Ai	V _{PP}	D _{OUT}
PGM inhibit	V _{IH}	X	X	X	V _{PP}	High Z
Product identification ⁽⁴⁾	V _{IL}	V _{IL}	X	$A9 = V_H^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A15 = V_{IL}$	V _{CC}	Identification code

Notes:

- 1. X can be V_{IL} or V_{IH} .
- 2. Refer to programming characteristics.
- 3. $V_H = 12.0 \pm 0.5 V$.
- 4. Two identifier words may be selected. All Ai inputs are held low (V_{IL}) , except A9, which is set to V_{H} , and A0, which is toggled low (V_{IL}) to select the manufacturer's identification word and high (V_{IH}) to select the device code word.
- 5. Standby V_{CC} current (I_{SB}) is specified with $V_{PP} = V_{CC}$. $V_{CC} > V_{PP}$ will cause a slight increase in I_{SB} .

Table 5-2. DC and AC operating conditions for read operation

		Atmel AT27C1024			
		-45	-70		
Operating toppo (sees)	Ind.	-40°C - 85°C	-40°C - 85°C		
Operating temp. (case)	Auto.				
V _{CC} power supply		5V ± 10%	5V ± 10%		





Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition		Min	Max	Units
	Input load current)/ O)/ to //	Ind.		±1	μΑ
I _{LI}	Input load current	$V_{IN} = OV \text{ to } V_{CC}$	Auto.		±5	μΑ
	Output leakage current	0\/ +0 \/	Ind.		±5	μΑ
ILO	Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$	Auto.		±10	μΑ
I _{PP1} ⁽²⁾	V _{PP} ⁽¹⁾⁾ read/standby current	$V_{PP} = V_{CC}$	$V_{PP} = V_{CC}$			μΑ
	V (1) standby surrent	I_{SB1} (CMOS), $\overline{CE} = V_C$	I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
I _{SB}	V _{CC} ⁽¹⁾ standby current	I_{SB2} (TTL), $\overline{CE} = 2.0 \text{ to}$		1	mA	
I _{CC}	V _{CC} active current	$f = 5MHz$, $I_{OUT} = 0mA$	$f = 5MHz$, $I_{OUT} = 0mA$, $\overline{CE} = V_{IL}$		30	mA
V _{IL}	Input low voltage				0.8	V
V _{IH}	Input high voltage			2.0	V _{CC} + 0.5	V
V _{OL}	Output low voltage	I _{OL} = 2.1mA			0.4	V
V _{OH}	Output high voltage	I _{OH} = -400μA	I _{OH} = -400μA			V

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} , and removed simultaneously with or after V_{PP} .

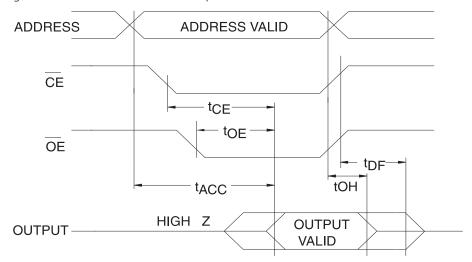
Table 5-4. AC characteristics for read operation

				Atmel AT	27C1024		
			_	-45 -70			
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t _{ACC} ⁽¹⁾	Address to output delay	$\overline{CE} = \overline{OE} = V_{IL}$		45		70	ns
t _{CE} ⁽¹⁾	CE to output delay	$\overline{OE} = V_{IL}$		45		70	ns
t _{OE} ⁽¹⁾	OE to output delay	CE = V _{IL}		20		25	ns
t _{DF} ⁽¹⁾	OE or CE high to output float, whichever occurred first			20		25	ns
t _{OH}	Output hold from address, \overline{CE} or \overline{OE} , whichever occurred first		7		7		ns

Note: 1. See AC waveforms for read operation.

^{2.} V_{PP} may be connected directly to V_{CC} , except during programming. The supply current would then be the sum of I_{CC} and I_{PP} .

Figure 5-1. AC waveforms for read operation⁽¹⁾



Notes:

- 1. Timing measurement reference level is 1.5V for -45. Input AC drive levels are $V_{IL} = 0.0V$ and $V_{IH} = 3.0V$. Timing measurement reference levels for all other speed grades are $V_{OL} = 0.8V$ and $V_{OH} = 2.0V$. Input AC drive levels are $V_{IL} = 0.45V$ and $V_{IH} = 2.4V$.
- 2. \overline{OE} may be delayed up to t_{CE} t_{OE} after the falling edge of \overline{CE} without impact on t_{CE} .
- 3. $\overline{\text{OE}}$ may be delayed up to t_{ACC} t_{OE} after the address is valid without impact on t_{ACC} .
- 4. This parameter is only sampled, and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

Table 5-5. Pin capacitance

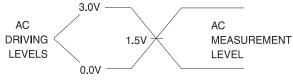
 $f = 1MHz, T = 25°C^{(1)}$

Symbol	Тур	Max	Units	Conditions
C _{IN}	4	10	pF	V _{IN} = 0V
C _{OUT}	8	12	pF	V _{OUT} = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

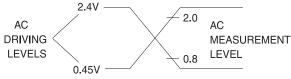
Figure 5-2. Input test waveforms and measurement levels

For -45 devices only:



 t_R , t_F < 5ns (10% to 90%)

For -70 devices only:

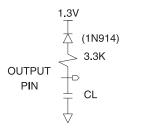


 t_R , t_F < 20 ns (10% to 90%)



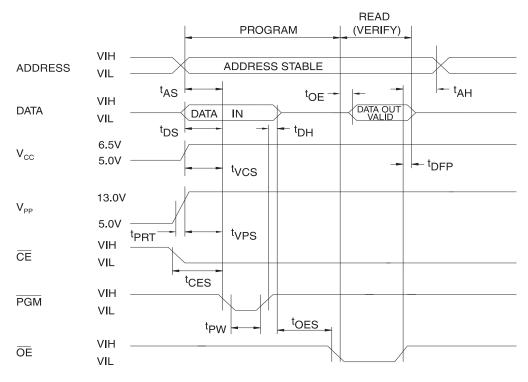


Figure 5-3. Output test load



Note: 1. $C_L = 100 pF$ including jig capacitance, except -45 devices, where $C_L = 30 pF$.

Figure 5-4. Programming waveforms (1)



Notes:

- 1. The input timing reference is 0.8V for $\rm V_{IL}$ and 2.0V for $\rm V_{IH}$
- 2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer.
- 3. When programming the Atmel AT27C1024, a $0.1\mu F$ capacitor is required across V_{pp} and ground to suppress sputious voltage transients.

Table 5-6. DC programming characteristics

$$T_A = 25 \pm 5$$
°C, $V_{CC} = 6.5 \pm 0.25$ V, $V_{PP} = 13.0 \pm 0.25$ V

			Limits		
Symbol	Parameter	Test conditions	Min	Max	Units
I _{LI}	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	μΑ
V _{IL}	Input low level		-0.6	0.8	V
V _{IH}	Input high level		2.0	V _{CC} + 0.1	V
V _{OL}	Output low voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output high voltage	I _{OH} = -400μA	2.4		V
I _{CC2}	V _{CC} supply current (program and verify)			50	mA
I _{PP2}	V _{PP} supply current	$\overline{CE} = \overline{PGM} = V_{IL}$		30	mA
V _{ID}	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_A = 25 \pm 5$ °C, $V_{CC} = 6.5 \pm 0.25$ V, $V_{PP} = 13.0 \pm 0.25$ V

			Lin		
Symbol	Parameter	Test conditions ⁽¹⁾	Min	Max	Units
t _{AS}	Address setup time		2		μs
t _{CES}	CE setup time		2		μs
t _{OES}	OE setup time	Input rise and fall times	2		μs
t _{DS}	Data setup time	(10% to 90%) 20ns	2		μs
t _{AH}	Address hold time	Input pulse levels	0		μs
t _{DH}	Data hold time	0.45V to 2.4V	2		μs
t _{DFP}	OE high to output float delay ⁽²⁾	Input timing reference level	0	130	ns
t _{VPS}	V _{PP} setup time	0.8V to 2.0V	2		μs
t _{VCS}	V _{CC} setup time		2		μs
t _{PW}	PGM program pulse width ⁽³⁾	Output timing reference level 0.8V to 2.0V	95	105	μs
t _{OE}	Data valid from OE	0.00 10 2.00		150	ns
t _{PRT}	V _{PP} pulse rise time during programming		50		ns

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously with or after V_{PP} .

- 2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
- 3. Program pulse width tolerance is $100\mu \sec \pm 5\%$.

Table 5-8. The Atmel AT27C1024 integrated product identification code

		Pins				Hex					
Codes	A0	015-08	07	06	O5	04	О3	02	01	00	data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device type	1	0	1	1	1	1	0	0	0	1	00F1

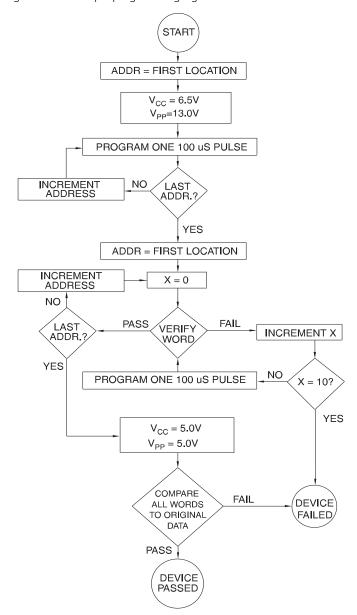




6. Rapid programming algorithm

A 100 μ s \overline{PGM} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μ s \overline{PGM} pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 100 μ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



7. Ordering information

Green Package (Pb/halide-free)

t _{ACC}	I _{CC} (mA)					
(ns)	Active	Standby	Atmel ordering code	Package	Lead finish	Operation range
45	30	0.1	AT27C1024-45JU AT27C1024-45PU	44J 40P6	Matte tin Matte tin	Industrial (-40°C to 85°C)
70	30	0.1	AT27C1024-70JU AT27C1024-70PU	44J 40P6	Matte tin Matte tin	Industrial (-40°C to 85°C)

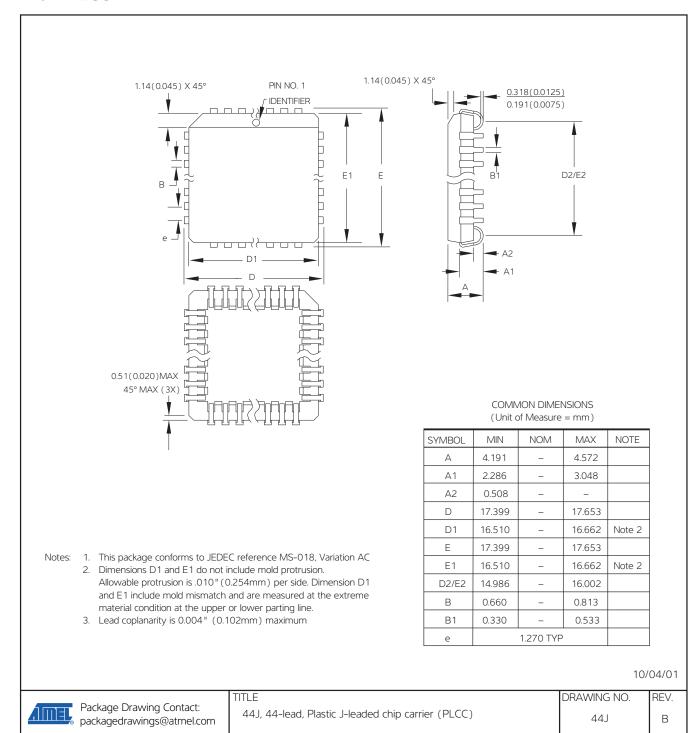
Package type			
44J 44-lead, plastic, J-leaded chip carrier (PLCC)			
40P6	40-lead, 0.600" wide, plastic, dual inline package (PDIP)		



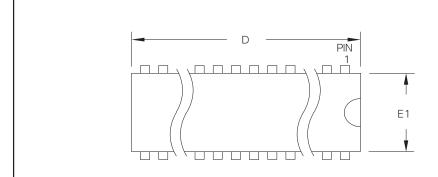


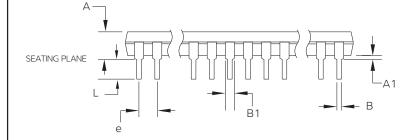
8. Packaging information

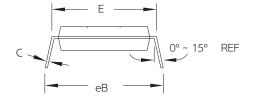
44J – PLCC



40P6 - PDIP







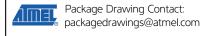
Notes: 1. This package conforms to JEDEC reference MS-011, Variation AC.

2. Dimensions D and E1 do not include mold Flash or Protrusion. Mold Flash or Protrusion shall not exceed 0.25mm (0.010").

COMMON DIMENSIONS (Unit of Measure = mm)

(Gracor Medada e Trant)					
SYMBOL	MIN	NOM	MAX	NOTE	
А	_	-	4.826		
Α1	0.381	-	_		
D	52.070	-	52.578	Note 2	
Е	15.240	-	15.875		
E1	13.462	-	13.970	Note 2	
В	0.356	-	0.559		
B1	1.041	-	1.651		
L	3.048	-	3.556		
С	0.203	-	0.381		
eB	15.494	_	17.526		
е	2.540 TYP				

09/28/01



40DC 40 lead (0.000 /4E 24 each \Alida \Alida \Dead's D	
40P6, 40-lead (0.600"/15.24mm Wide) Plastic Du Inline Package (PDIP)	al

DRAWING NO. REV. 40P6 B





9. Revision history

Doc. Rev.	Date	Comments	
0019N	04/2011	Remove VSOP package	
		Add lead finish to ordering information	
0019M	12/2007		



Atmel Corporation

2325 Orchard Parkway San Jose, CA 95131 USA

Tel: (+1) (408) 441-0311 **Fax:** (+1) (408) 487-2600

www.atmel.com

Atmel Asia Limited

Unit 01-5 & 16, 19F BEA Tower, Millennium City 5 418 Kwun Tong Road Kwun Tong, Kowloon HONG KONG

Tel: (+852) 2245-6100 **Fax:** (+852) 2722-1369

Atmel Munich GmbH

Business Campus Parkring 4 D-85748 Garching b. Munich GERMANY

Tel: (+49) 89-31970-0 **Fax:** (+49) 89-3194621

Atmel Japan

9F, Tonetsu Shinkawa Bldg. 1-24-8 Shinkawa Chuo-ku, Tokyo 104-0033 JAPAN

Tel: (+81) (3) 3523-3551 **Fax:** (+81) (3) 3523-7581

© 2011 Atmel Corporation. All rights reserved. / Rev.: 0019N-EPROM-4/11

Atmel[®], logo and combinations thereof, and others are registered trademarks or trademarks of Atmel Corporation or its subsidiaries. Other terms and product names may be trademarks of others.

Disclaimer: The information in this document is provided in connection with Atmel products. No license, express or implied, by estoppel or otherwise, to any intellectual property right is granted by this document or in connection with the sale of Atmel products. EXCEPT AS SET FORTH IN THE ATMEL TERMS AND CONDITIONS OF SALES LOCATED ON THE ATMEL WEBSITE, ATMEL ASSUMES NO LUABILITY WHATSOEVER AND DISCLAIMS ANY EXPRESS, IMPLIED OR STATUTORY WARRANTY OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, OR NON-INFRINGEMENT. IN NO EVENT SHALL ATMEL BE LIABLE FOR ANY DIRECT, CONSEQUENTIAL, PUNITIVE, SPECIAL OR INCIDENTAL DAMAGES (INCLUDING, WITHOUT LIMITATION), DAMAGES FOR LOSS AND PROFITS, BUSINESS INTERRUPTION, OR LOSS OF INFORMATION) ARISING OUT OF THE USE OR INABILITY TO USE THIS DOCUMENT, EVEN IF ATMEL HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES. Atmel makes no representations or warranties with respect to the accuracy or completeness of the contents of this document and reserves the right to make changes to specifications and products descriptions at any time without notice. Atmel does not make any commitment to update the information contained herein. Unless specifically provided otherwise, Atmel products are not intended, authorized, or warranted for use as components in applications intended to support or sustain life.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Microchip:

AT27C1024-15VI AT27C1024-15PI AT27C1024-15JI AT27C1024-15JC AT27C1024-70JC AT27C1024-70PC

AT27C1024-55PI AT27C1024-55JC AT27C1024-45JI AT27C1024-45JC AT27C1024-10JC AT27C1024-70JI

AT27C1024-90JC AT27C1024-12PC AT27C1024-12JC AT27C1024-12VC AT27C1024-45PI AT27C1024-70PI

AT27C1024-45PU AT27C1024-70PU AT27C1024-45JU AT27C1024-70JU AT27C1024-45VI AT27C1024-70VI

AT27C1024-12JI AT27C1024-70JU-T AT27C1024-45JU-T